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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	5820
Number of Logic Elements/Cells	74496
Total RAM Bits	5750784
Number of I/O	360
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx75t-2ffg784c

Table 3: DC Characteristics Over Recommended Operating Conditions (1)(2)

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	—	—	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	—	—	V
I_{REF}	V_{REF} leakage current per pin	—	—	10	μA
I_L	Input or output leakage current per pin (sample-tested)	—	—	10	μA
$C_{IN}^{(3)}$	Die input capacitance at the pad	—	—	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 2.5V$	20	—	80	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.8V$	8	—	40	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.5V$	5	—	30	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.2V$	1	—	20	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 2.5V$	3	—	80	μA
I_{BATT}	Battery supply current	—	—	150	nA
n	Temperature diode ideality factor	—	1.0002	—	n
r	Series resistance	—	5	—	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CC0Q}	Quiescent V_{CC0} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT} , V_{CCAUX} , and V_{CCO} to meet the power-up current requirements listed in [Table 5](#). V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from [Table 5](#). The device will have no physical damage or reliability concerns if V_{CCINT} , V_{CCAUX} , and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCR, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see [Table 27: GTH Transceiver Power Supply Sequencing](#). There are no sequencing requirements for the GTX transceivers power supplies.

[Table 5](#) shows the minimum current, in addition to I_{CCQ} , that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in [Table 4](#) and [Table 5](#) are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT} , V_{CCAUX} , and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: Power-On Current for Virtex-6 Devices

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	Units
	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	
XC6VLX75T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX760	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	-	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	-	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	-	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	-	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.825	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.785	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.715	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	350	-	840	mV
	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XQ devices		350	-	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	Common-mode input voltage = 1.25V	100	-	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

LVPECL DC Specifications (LVPECL_25)

These values are valid when driving a 100Ω differential load only, i.e., a 100Ω resistor between the two receiver pins. The V_{OH} levels are 200 mV below standard LVPECL levels and are compatible with devices tolerant of lower common-mode ranges. [Table 11](#) summarizes the DC output specifications of LVPECL. For more information on using LVPECL, see [UG361: Virtex-6 FPGA SelectIO Resources User Guide](#).

Table 11: LVPECL DC Specifications

Symbol	DC Parameter	Min	Typ	Max	Units
V_{OH}	Output High Voltage	$V_{CC} - 1.025$	1.545	$V_{CC} - 0.88$	V
V_{OL}	Output Low Voltage	$V_{CC} - 1.81$	0.795	$V_{CC} - 1.62$	V
V_{ICM}	Input Common-Mode Voltage	0.6	–	2.2	V
V_{IDIFF}	Differential Input Voltage ⁽¹⁾⁽²⁾	0.100	–	1.5	V

Notes:

1. Recommended input maximum voltage not to exceed $V_{CCAUX} + 0.2V$.
2. Recommended input minimum voltage not to go below $-0.5V$.

eFUSE Read Endurance

[Table 12](#) lists the maximum number of read cycle operations expected. For more information, see [UG360: Virtex-6 FPGA Configuration User Guide](#).

Table 12: eFUSE Read Endurance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

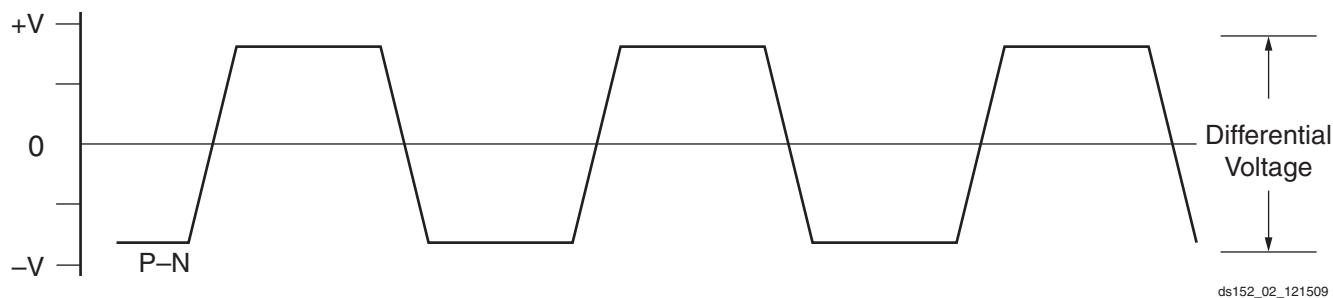


Figure 2: Differential Peak-to-Peak Voltage

Table 18 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 18: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	210	800	2000	mV
R_{IN}	Differential input resistance	90	100	130	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTX Transceiver Switching Characteristics

Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further information.

Table 19: GTX Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F_{GTXMAX}	Maximum GTX transceiver data rate	6.6	6.6	5.0	5.0	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	3.3 ⁽¹⁾	3.3 ⁽¹⁾	2.7	2.7	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	1.2	1.2	GHz

Notes:

- See Table 14 for MGTAVCC requirements when PLL frequency is greater than 2.7 GHz.

Table 20: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	150	150	125	100	MHz

GTH Transceiver DC Input and Output Levels

Table 30 summarizes the DC output specifications of the GTH transceivers in Virtex-6 FPGAs. Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further details.

Table 30: GTH Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
D _{VPPIN}	Differential peak-to-peak input voltage	External AC coupled	175	—	1200	mV
D _{VPPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	800	—	1200	mV
R _{IN}	Differential input resistance		80	100	120	Ω
R _{OUT}	Differential output resistance		80	100	120	Ω
T _{OSKew}	Transmitter output pair (TXP and TXN) intra-pair skew		—	2	—	ps
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		—	100	—	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

Table 31 summarizes the DC specifications of the clock input of the GTH transceiver. Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further details.

Table 31: GTH Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V _{IDIFF}	Differential peak-to-peak input voltage	≤ 600 MHz	500	—	1600	mV
		> 600 MHz	600	—	1600	mV
R _{IN}	Differential input resistance		80	100	120	Ω
C _{EXT}	Required external AC coupling capacitor		—	100	—	nF

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVCMOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns	
LVCMOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns	
LVCMOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns	
LVCMOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns	
LVCMOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns	
LVCMOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns	
LVCMOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns	
LVCMOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns	
LVCMOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns	
LVCMOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns	
LVCMOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns	
LVCMOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns	
LVCMOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns	
LVCMOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns	
LVCMOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns	
LVCMOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns	
LVCMOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns	
LVCMOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns	
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns	
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns	
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns	
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDCI_DV2_18	0.61	0.72	0.73	1.81	2.36	1.98	1.81	2.36	1.98	ns	
LVDCI_DV2_15	0.73	0.85	0.85	1.77	2.30	1.98	1.77	2.30	1.98	ns	
LVPECL_25	0.94	1.09	1.08	1.49	2.68	1.64	1.49	2.68	1.64	ns	
HSTL_I_12	0.91	1.06	1.06	1.60	2.48	1.74	1.60	2.48	1.74	ns	
HSTL_I_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns	
HSTL_II_DCI	0.91	1.06	1.06	1.49	2.39	1.66	1.49	2.39	1.66	ns	
HSTL_II_T_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns	
HSTL_III_DCI	0.91	1.06	1.06	1.45	2.48	1.61	1.45	2.48	1.61	ns	
HSTL_I_DCI_18	0.91	1.06	1.06	1.53	2.44	1.66	1.53	2.44	1.66	ns	
HSTL_II_DCI_18	0.91	1.06	1.06	1.46	2.41	1.59	1.46	2.41	1.59	ns	
HSTL_II_T_DCI_18	0.91	1.06	1.06	1.53	2.43	1.66	1.53	2.43	1.66	ns	
HSTL_III_DCI_18	0.91	1.06	1.06	1.54	2.50	1.67	1.54	2.50	1.67	ns	
DIFF_HSTL_I_18	0.94	1.09	1.08	1.58	2.30	1.72	1.58	2.30	1.72	ns	
DIFF_HSTL_I_DCI_18	0.94	1.09	1.08	1.53	2.21	1.66	1.53	2.21	1.66	ns	
DIFF_HSTL_I	0.94	1.09	1.08	1.56	2.28	1.71	1.56	2.28	1.71	ns	
DIFF_HSTL_I_DCI	0.94	1.09	1.08	1.50	2.28	1.64	1.50	2.28	1.64	ns	
DIFF_HSTL_II_18	0.94	1.09	1.08	1.62	2.33	1.78	1.62	2.33	1.78	ns	
DIFF_HSTL_II_DCI_18	0.94	1.09	1.08	1.46	2.18	1.59	1.46	2.18	1.59	ns	
DIFF_HSTL_II_T_DCI_18	0.94	1.09	1.08	1.53	2.22	1.66	1.53	2.22	1.66	ns	
DIFF_HSTL_II	0.94	1.09	1.08	1.56	2.29	1.72	1.56	2.29	1.72	ns	
DIFF_HSTL_II_DCI	0.94	1.09	1.08	1.49	2.26	1.66	1.49	2.26	1.66	ns	
SSTL2_I_DCI	0.91	1.06	1.06	1.53	2.51	1.68	1.53	2.51	1.68	ns	
SSTL2_II_DCI	0.91	1.06	1.06	1.50	2.50	1.69	1.50	2.50	1.69	ns	
SSTL2_II_T_DCI	0.91	1.06	1.06	1.53	2.52	1.68	1.53	2.52	1.68	ns	
SSTL18_I	0.91	1.06	1.06	1.58	2.48	1.73	1.58	2.48	1.73	ns	
SSTL18_II	0.91	1.06	1.06	1.50	2.46	1.66	1.50	2.46	1.66	ns	
SSTL18_I_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns	
SSTL18_II_DCI	0.91	1.06	1.06	1.47	2.41	1.62	1.47	2.41	1.62	ns	
SSTL18_II_T_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns	
SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns	
SSTL15_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns	
DIFF_SSTL2_I	0.94	1.09	1.08	1.60	2.34	1.74	1.60	2.34	1.74	ns	
DIFF_SSTL2_I_DCI	0.94	1.09	1.08	1.53	2.25	1.68	1.53	2.25	1.68	ns	
DIFF_SSTL2_II	0.94	1.09	1.08	1.54	2.29	1.71	1.54	2.29	1.71	ns	
DIFF_SSTL2_II_DCI	0.94	1.09	1.08	1.50	2.23	1.69	1.50	2.23	1.69	ns	
DIFF_SSTL2_II_T_DCI	0.94	1.09	1.08	1.53	2.26	1.68	1.53	2.26	1.68	ns	
DIFF_SSTL18_I	0.94	1.09	1.08	1.58	2.22	1.73	1.58	2.22	1.73	ns	
DIFF_SSTL18_I_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
DIFF_SSTL18_II	0.94	1.09	1.08	1.50	2.27	1.66	1.50	2.27	1.66	ns	
DIFF_SSTL18_II_DCI	0.94	1.09	1.08	1.47	2.20	1.62	1.47	2.20	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns	
DIFF_SSTL15	0.91	1.06	1.06	1.54	2.25	1.69	1.54	2.25	1.69	ns	
DIFF_SSTL15_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns	
DIFF_SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns	

Table 46: IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{IOTPHZ}	T input to Pad high-impedance	0.86	0.92	0.99	0.99	ns

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{DCK/T_OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ -0.08	0.50/ -0.08	0.54/ -0.08	0.54/ -0.08	0.69/ -0.11	ns
T _O OCECK/T _O CKOCE	OCE pin Setup/Hold with respect to CLK	0.17/ -0.03	0.20/ -0.03	0.22/ -0.03	0.27/ -0.05	0.27/ -0.04	ns
T _S SRCK/T _O CKSR	SR pin Setup/Hold with respect to CLK	0.59/ -0.24	0.62/ -0.24	0.54/ -0.08	0.54/ -0.08	0.79/ -0.35	ns
T _T TCK/T _O CKT	T1/T2 pins Setup/Hold with respect to CLK	0.44/ -0.07	0.51/ -0.07	0.56/ -0.07	0.60/ -0.10	0.68/ -0.13	ns
T _T TCECK/T _O CKTCE	TCE pin Setup/Hold with respect to CLK	0.15/ -0.04	0.19/ -0.04	0.21/ -0.04	0.27/ -0.05	0.29/ -0.05	ns
Combinatorial							
T _D OQ	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _O CKQ	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _R Q	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _G SRQ	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _R PW	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Table 57: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{RCKC_WE} /T _{RCKC_WREN}	Write Enable (WE) input (Block RAM only)	0.44/ 0.19	0.47/ 0.25	0.52/ 0.35	0.67/ 0.24	ns, Min
T _{RCKC_WREN} /T _{RCKC_RDEN}	WREN FIFO inputs	0.47/ 0.26	0.50/ 0.27	0.55/ 0.30	0.68/ 0.31	ns, Min
T _{RCKC_RDEN} /T _{RCKC_WREN}	RDEN FIFO inputs	0.46/ 0.26	0.50/ 0.27	0.55/ 0.30	0.67/ 0.31	ns, Min
Reset Delays						
T _{RCO_FLAGS}	Reset RST to FIFO Flags/Pointers ⁽¹⁰⁾	0.90	0.98	1.10	1.23	ns, Max
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	FIFO reset timing ⁽¹¹⁾	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
Maximum Frequency						
F _{MAX}	Block RAM in TDP and SDP modes (Write First and No Change modes)	600	540	450	340	MHz
	Block RAM (Read First mode)	525	475	400	275	MHz
	Block RAM (SDP mode) ⁽¹²⁾	525	475	400	275	MHz
F _{MAX_CASCADE}	Block RAM Cascade (Write First and No Change modes)	550	490	400	300	MHz
	Block RAM Cascade (Read First mode)	475	425	350	235	MHz
F _{MAX_FIFO}	FIFO in all modes	600	540	450	340	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	450	400	325	250	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. T_{RCKO_DI} includes both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. The FIFO reset must be asserted for at least three positive clock edges.
12. When using ISE software v12.4 or later, if the RDADDR_COLLISION_HWCONFIG attribute is set to PERFORMANCE or the block RAM is in single-port operation, then the faster F_{MAX} for WRITE_FIRST/NO_CHANGE modes apply.

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
T _{DSPDO_{PCIN, CARRYCASCIN, MULTSIGNIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}}	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_PREG}	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_PREG}	CLK (PREG) to {CARRYCASOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_MREG}	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MREG}	CLK (MREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
T _{DSPCKO_{P, CARRYOUT}_ADREG_MULT}	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_ADREG_MULT}	CLK (ADREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}_MULT}	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}}	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
T _{DSPCKO_{P, CARRYOUT}_CREG}	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
T _{DSPCKO_{P, CARRYOUT}_DREG_MULT}	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}_MULT}	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}}	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_DREG_MULT}	CLK (DREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_CREG}	CLK (CREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{MMCMDCK_DI} / T _{MMCMCKD_DI}	DI Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T _{MMCMDCK_DEN} / T _{MMCMCKD_DEN}	DEN Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T _{MMCMDCK_DWE} / T _{MMCMCKD_DWE}	DWE Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T _{MMCMCKO_DO}	CLK to out of DO ⁽³⁾	2.60	3.02	3.64	3.68	ns
T _{MMCMCKO_DRDY}	CLK to out of DRDY	0.32	0.34	0.38	0.38	ns

Notes:

1. To support longer delays in configuration, use the design solutions described in [UG360: Virtex-6 FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
3. DO will hold until next DRP operation.

Clock Buffers and Networks

Table 60: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-2	-1	-1L	
T _{BCCCK_CE} / T _{BCCKC_CE} ⁽¹⁾	CE pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
T _{BCCCK_S} / T _{BCCKC_S} ⁽¹⁾	S pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
T _{BGCKO_O} ⁽²⁾	BUFGCTRL delay from I0/I1 to O	All	0.07	0.08	0.10	0.10	ns
Maximum Frequency							
F _{MAX}	Global clock tree (BUFG)	All except LX760	800	750	700	667	MHz
		LX760	N/A	700	700	667	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX_VIRTEX4 primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BGCKO_O} values.

Table 61: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BLOCKO_O}	Clock to out delay from I to O	0.14	0.16	0.18	0.21	ns
Maximum Frequency						
F _{MAX}	I/O clock tree (BUFIO)	800	800	710	710	MHz

Table 62: Regional Clock Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BRCKO_O}	Clock to out delay from I to O	0.56	0.62	0.73	0.82	ns
T _{BRCKO_O_BYP}	Clock to out delay from I to O with Divide Bypass attribute set	0.28	0.31	0.36	0.41	ns

Table 66: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
T _C KOFMMCMGC	Global Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.34	2.50	2.77	2.85	ns
		XC6VLX130T	2.35	2.51	2.78	2.87	ns
		XC6VLX195T	2.36	2.52	2.79	2.88	ns
		XC6VLX240T	2.36	2.52	2.79	2.88	ns
		XC6VLX365T	2.37	2.53	2.79	2.89	ns
		XC6VLX550T	N/A	2.55	2.82	2.93	ns
		XC6VLX760	N/A	2.54	2.82	2.92	ns
		XC6VSX315T	2.35	2.51	2.79	2.87	ns
		XC6VSX475T	N/A	2.43	2.70	2.79	ns
		XC6VHX250T	2.36	2.53	2.80	N/A	ns
		XC6VHX255T	2.46	2.63	2.91	N/A	ns
		XC6VHX380T	2.39	2.59	2.83	N/A	ns
		XC6VHX565T	N/A	2.54	2.81	N/A	ns
		XQ6VLX130T	N/A	2.51	2.78	2.87	ns
		XQ6VLX240T	N/A	2.52	2.79	2.88	ns
		XQ6VLX550T	N/A	N/A	2.82	2.93	ns
		XQ6VSX315T	N/A	2.51	2.79	2.87	ns
		XQ6VSX475T	N/A	N/A	2.70	2.79	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSMMC} /T _{PHMMC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ -0.25	1.69/ -0.25	1.86/ -0.25	1.91/ -0.15	ns
		XC6VLX130T	1.64/ -0.25	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XC6VLX195T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX240T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX365T	1.66/ -0.25	1.79/ -0.25	1.97/ -0.25	2.02/ -0.15	ns
		XC6VLX550T	N/A	1.97/ -0.24	2.16/ -0.24	2.19/ -0.14	ns
		XC6VLX760	N/A	2.39/ -0.20	2.63/ -0.20	2.21/ -0.10	ns
		XC6VSX315T	1.67/ -0.25	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XC6VSX475T	N/A	1.98/ -0.29	2.17/ -0.29	2.21/ -0.20	ns
		XC6VHX250T	1.63/ -0.24	1.76/ -0.24	1.94/ -0.24	N/A	ns
		XC6VHX255T	1.63/ -0.19	1.76/ -0.19	1.99/ -0.19	N/A	ns
		XC6VHX380T	1.80/ -0.23	1.94/ -0.23	2.13/ -0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ -0.08	2.13/ -0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XQ6VLX240T	N/A	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ -0.24	2.19/ -0.14	ns
		XQ6VSX315T	N/A	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ -0.29	2.21/ -0.20	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T _{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T _{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T _{DCD_BUFO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T _{BUFIOSKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T _{BUFIOSKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T _{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

1. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
2. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Table 72: Package Skew

Symbol	Description	Device	Package	Value	Units	
TPKGSKW	Package Skew ⁽¹⁾	XC6VLX75T	FF484	95	ps	
			FF784	146	ps	
		XC6VLX130T	FF484	95	ps	
			FF784	146	ps	
			FF1156	165	ps	
			XC6VLX195T	FF784	145	ps
				FF1156	182	ps
		XC6VLX240T		FF784	146	ps
			FF1156	182	ps	
			FF1759	187	ps	
		XC6VLX365T	FF1156	189	ps	
			FF1759	184	ps	
		XC6VLX550T	FF1759	196	ps	
			FF1760	249	ps	
		XC6VLX760	FF1760	236	ps	
		XC6VSX315T	FF1156	168	ps	
			FF1759	190	ps	
		XC6VSX475T	FF1156	168	ps	
			FF1759	204	ps	
		XC6VHX250T	FF1154	166	ps	
		XC6VHX255T	FF1155	168	ps	
			FF1923	228	ps	
		XC6VHX380T	FF1154	159	ps	
			FF1155	172	ps	
			FF1923	227	ps	
			FF1924	220	ps	
		XC6VHX565T	FF1923	232	ps	
			FF1924	197	ps	
XQ6VLX130T	RF784	146	ps			
	RF1156	165	ps			
	FFG1156	165	ps			
XQ6VLX240T	RF784	146	ps			
	RF1156	182	ps			
	FFG1156	182	ps			
	RF1759	187	ps			
XQ6VLX550T	RF1759	196	ps			
XQ6VSX315T	RF1156	168	ps			
	FFG1156	168	ps			
	RF1759	190	ps			
XQ6VSX475T	RF1156	168	ps			
	FFG1156	168	ps			
	RF1759	204	ps			

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest flight time to longest flight time from Pad to Ball (7.0 ps per mm).
- Package trace length information is available for these device/package combinations. This information can be used to deskew the package.

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2L. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .

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